TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type ( $\pi$ -MOSVI)

# 2SK3797

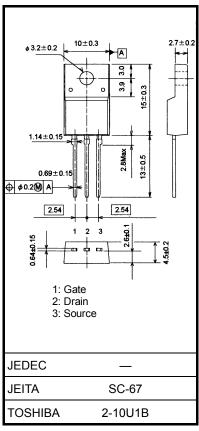
### **Switching Regulator Applications**

Unit: mm

- Low drain-source ON resistance: RDS (ON) =  $0.32 \Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 7.5 \text{ S (typ.)}$
- Low leakage current:  $I_{DSS} = 100 \, \mu \, A \, (V_{DS} = 600 \, V)$
- Enhancement model:  $V_{th} = 2.0 \sim 4.0 \text{ V} \text{ (V}_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA)}$

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristic		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	600	V	
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	600	V	
Gate-source voltage		$V_{GSS}$	±30	V	
	DC (Note 1)	I <sub>D</sub>	13		
Drain current	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	52	Α	
Drain power dissipati	on (Tc = 25°C)	P <sub>D</sub>	50	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	1033	mJ	
Avalanche current		I <sub>AR</sub>	13	Α	
Repetitive avalanche	energy (Note 3)	E <sub>AR</sub>	5.0	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

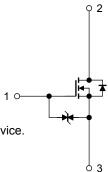


Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.5	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W



- Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.
- Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial), L = 10.7 mH,  $I_{AR} = 13 \text{ A}$ ,  $R_G = 25 \Omega$
- Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



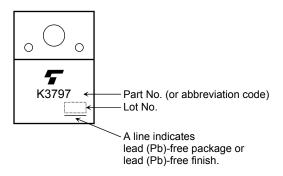
# Electrical Characteristics (Ta = 25°C)

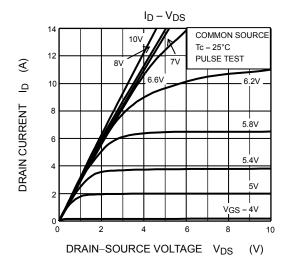
Char	Characteristic Symbol		Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА
Gate-source brea	akdown voltage	V (BR) GSS	$I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$	±30	_	_	V
Drain cutoff curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	_	_	100	
Drain-source brea	akdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	600	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 6.5 A	_	0.32	0.43	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 7.0 A	2.1	7.5		S
Input capacitance	9	C <sub>iss</sub>			3100	_	
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	20	_	pF
Output capacitance		C <sub>oss</sub>		_	270	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $V_{OV}$ $V$	_	60	_	. ns
	Turn-on time	t <sub>on</sub>		_	110	_	
	Fall time	t <sub>f</sub>			50		
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, t <sub>w</sub> = 10 μs	_	215	_	
Total gate charge		Qg		_	62	_	
Gate-source charge		Qgs	$V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}$	_	40	_	nC
Gate-drain charge		Q <sub>gd</sub>		_	22	_	

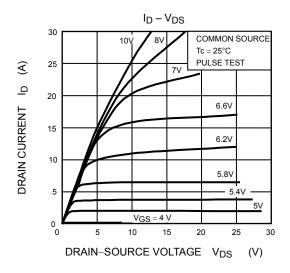
# Source-Drain Ratings and Characteristics (Ta = 25°C)

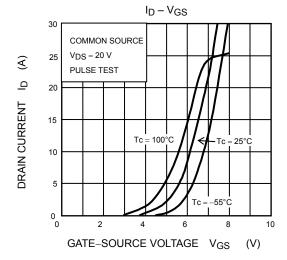
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current	(Note 1)	I <sub>DR</sub>	_		_	13	Α
Pulse drain reverse current	(Note 1)	I <sub>DRP</sub>	_	_	_	52	Α
Forward voltage (diode)		$V_{DSF}$	$I_{DR} = 13 \text{ A}, V_{GS} = 0 \text{ V}$		_	-1.7	V
Reverse recovery time		t <sub>rr</sub>	I <sub>DR</sub> = 13 A, V <sub>GS</sub> = 0 V,	_	1050	_	ns
Reverse recovery charge		Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs	_	15	_	μС

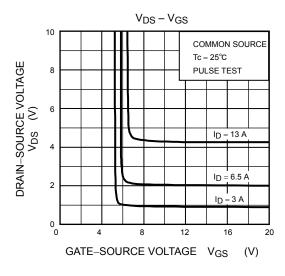
## Marking

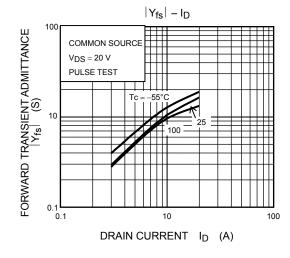


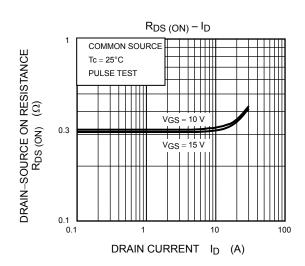




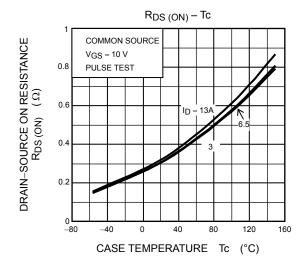


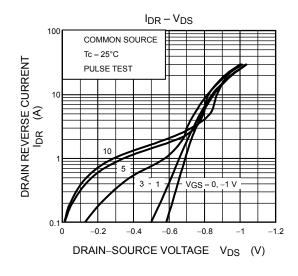


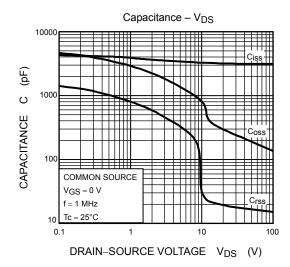


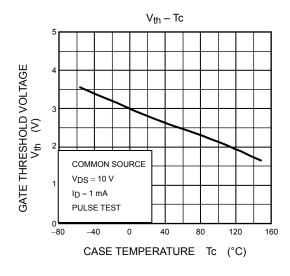


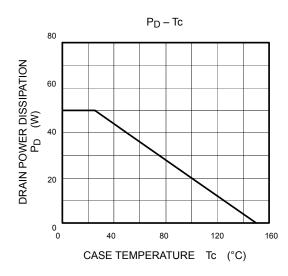
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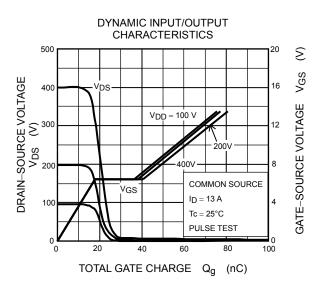




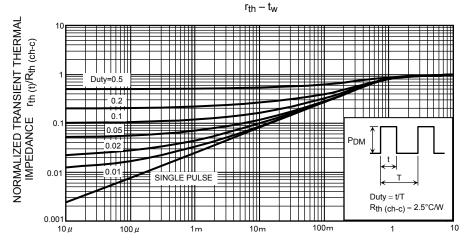




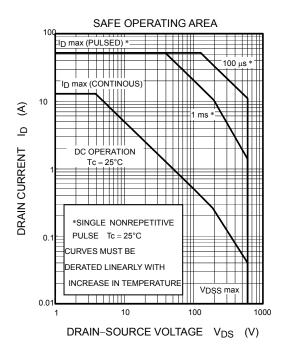


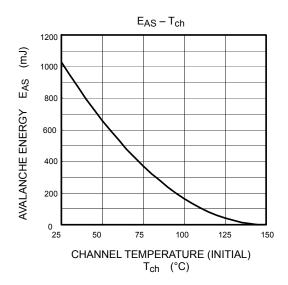


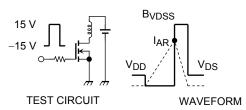
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PULSE WIDTH  $t_w$  (s)







$$R_G = 25 \Omega$$
  
 $V_{DD} = 90 \text{ V, L} = 10.7 \text{mH}$   $EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD}\right)$ 

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